| Form PTO 1449 (Modified) | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | ATTY DOCKET NO. 245959US2 | SERIAL NO. NEW APPLICATION |
|---|---|---|---|
| LIST OF REFERENCES CITED BY APPLICANT | | APPLICANT Masakiyo MATSUMURA, et al. | |
| | | FILING DATE HEREWITH | GROUP |

### U.S. PATENT DOCUMENTS

| EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB CLASS | FILING DATE IF APPROPRIATE |
|---|---|---|---|---|---|---|---|
| | AA | | | | | | |
| | AB | | | | | | |
| | AC | | | | | | |
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### FOREIGN PATENT DOCUMENTS

| | | DOCUMENT NUMBER | DATE | COUNTRY | TRANSLATION YES | NO |
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| | AO | | | | | |
| | AP | | | | | |
| | AQ | | | | | |
| | AR | | | | | |
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| | AT | | | | | |
| | AU | | | | | |

### OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

| RK | AV | Masakiyo MATSUMURA, "Preparation of Ultra-Large Grain Silicon Thin-Films by Excimer-Laser", SURFACE SCIENCE, Vol. 21, No.5, March 2000, pp. 278-287 |
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| RK | AW | M. NAKATA, et al., "Two-Dimensionally Position-Controlled Ultra-Large Grain Growth Based on Phase-Modulated Excimer-Laser Annealing Method", ELECTROCHEMICAL SOCIETY PROCEEDINGS, Vol. 2000-31, pgs.148-153 |
| RK | AX | Mitsuru NAKATA, et al., "A New Nucleation-Site-Control Excimer-Laser-Crystallization Method", JAPANESE JOURNAL OF APPLIED PHYSICS, PART 1 REGULAR PAPERS, SHORT NOTES & REVIEW PAPERS, Vol. 45 No. 5A, May 2001, pgs. 3049-3054 |
| RK | AY | Chang-Ho OH, " Optimization of phase-modulated excimer-laser annealing method for growing highly-packed large-grains in Si thin-films, APPLIED SURFACE SCIENCE 154-155, 2000, pgs. 105-111 |
| RK | AZ | M. MATSUMURA, "Advanced Laser-Crystallization Technologies of Si for High-Performance TFTs, ALTEDEC, pgs. 263-266 |

☐ Additional References sheet(s) attached

/Robert Kunemund/

Examiner

Date Considered **06/12/2006**

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.